

Microscopy innovations for Diamond Phase III

Ian Robinson
Diamond Fellow
Surface & Interface Village

"Away day"
Abingdon
July 2006



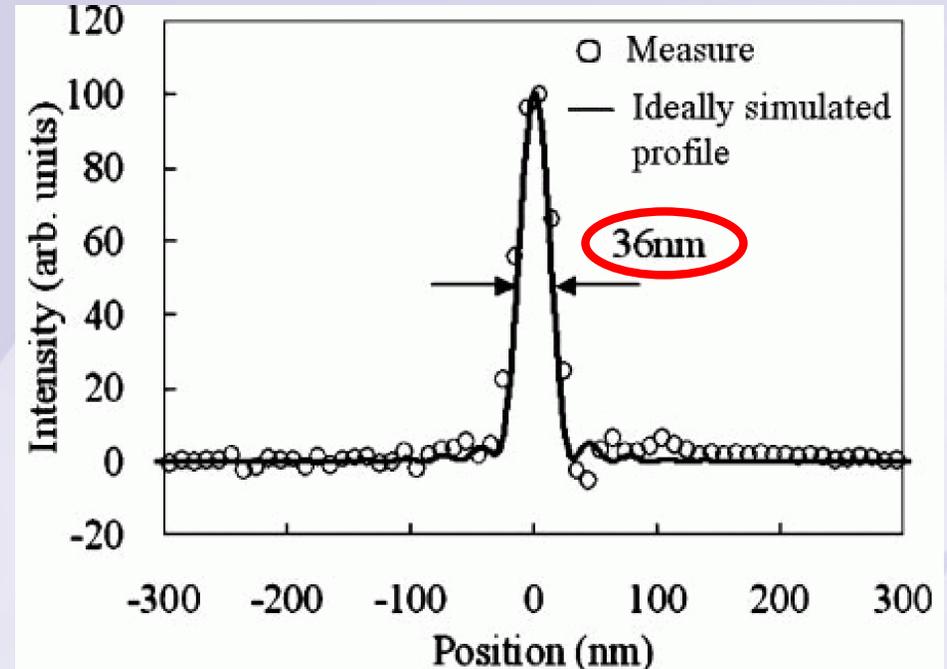
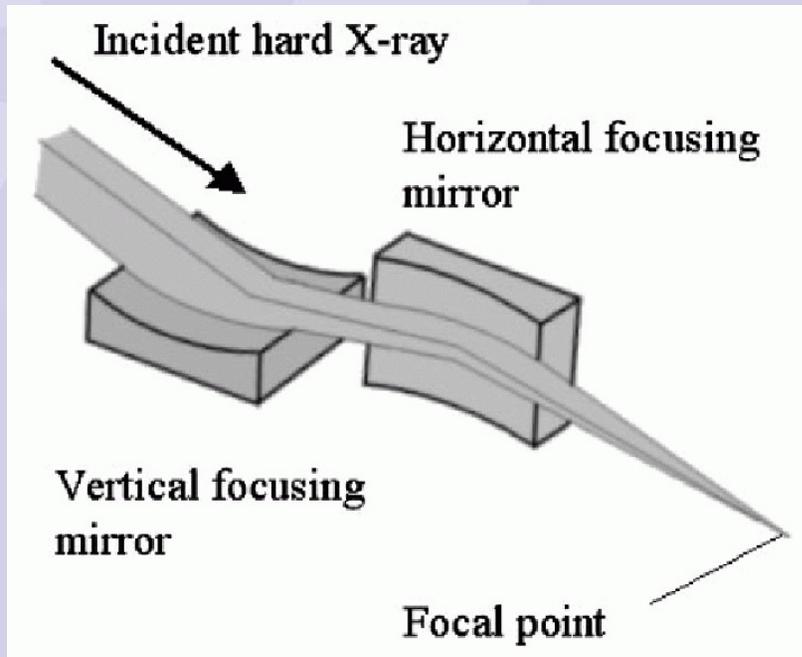
Expert Contributions from

- Franz Pfeiffer (SLS)
- Qun Shen (APS)
- Yong Chu (APS)
- Christoph Rau (APS)
- Paul Fenter (ANL)

Menu of X-ray Microscopies

- Hard / ~~Soft~~ X-rays
- ~~Scanning~~ / Full-field
- Phase / Amplitude contrast
- Coherent / Incoherent illumination
- Magnified / Actual size
- Diffraction (dark field) / Transmission

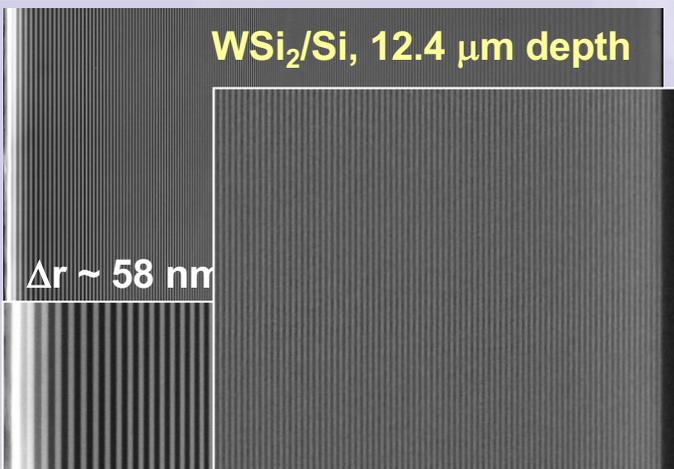
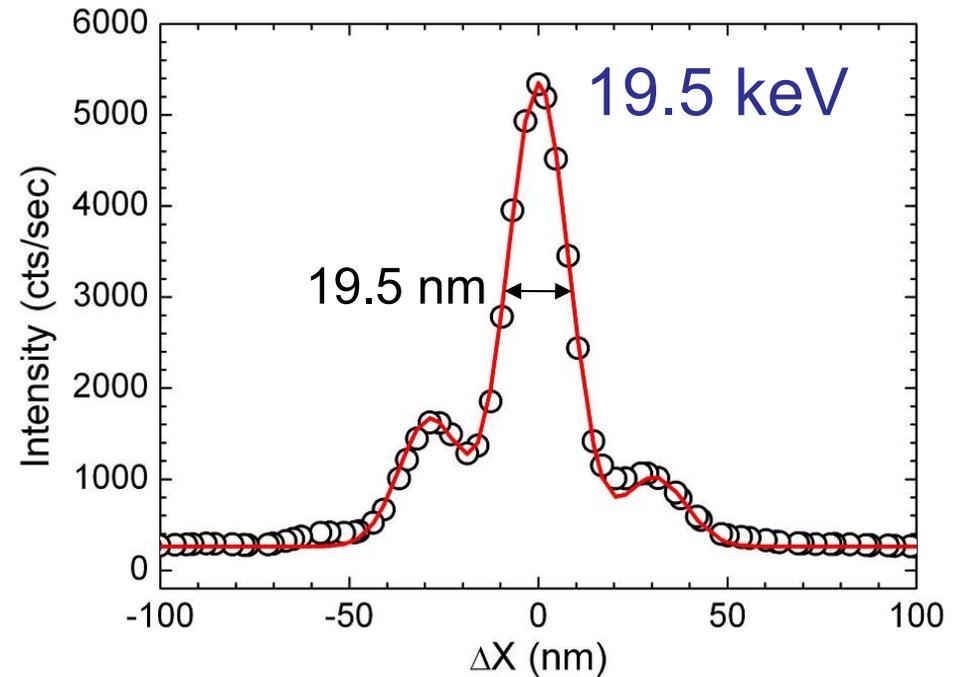
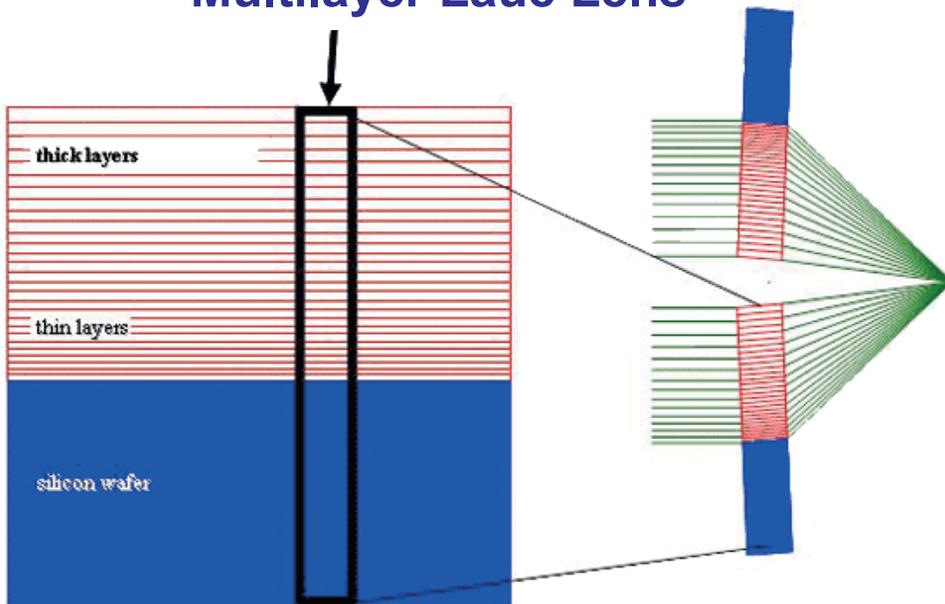
Nanoprobe Advances



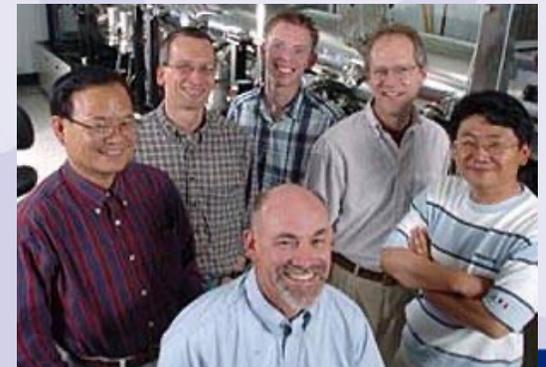
- H. Mimura et al, JJAP 44 L539 (2005) U. Osaka
- 2 nm peak to valley, 0.1 nm RMS, Pt mirrors
- 1-km-long beamline (BL29XUL) Spring-8 15keV
- Elastic Emission Machining (EEM)

Advanced Focusing Optics: Pathway for 5 nm Focusing of Hard X-rays (Q. Shen)

Multilayer Laue Lens



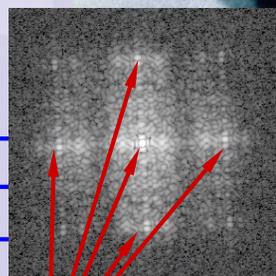
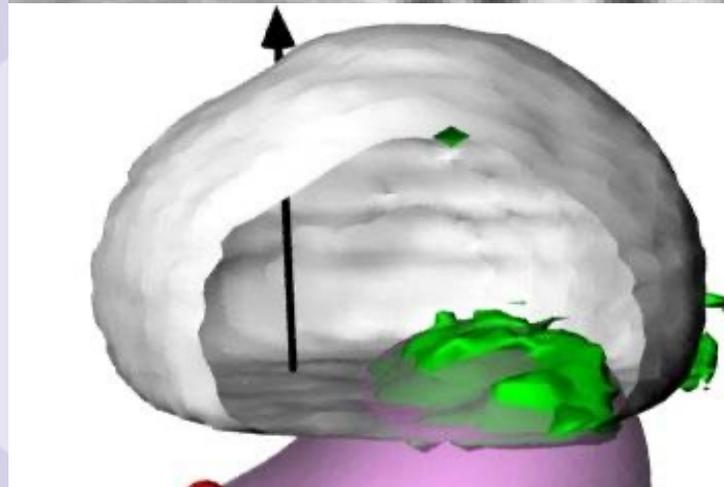
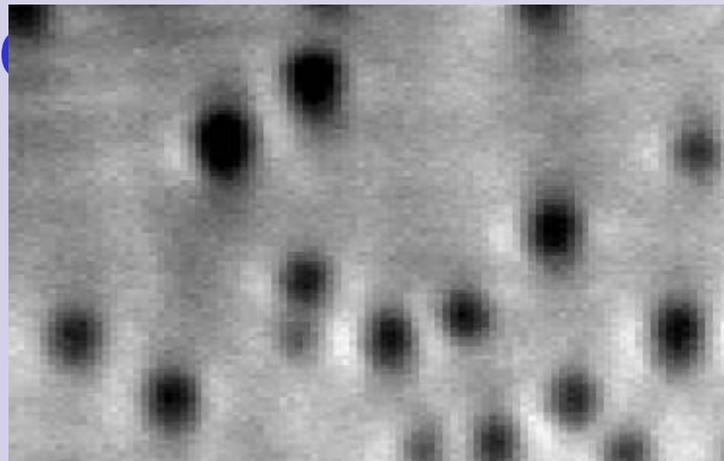
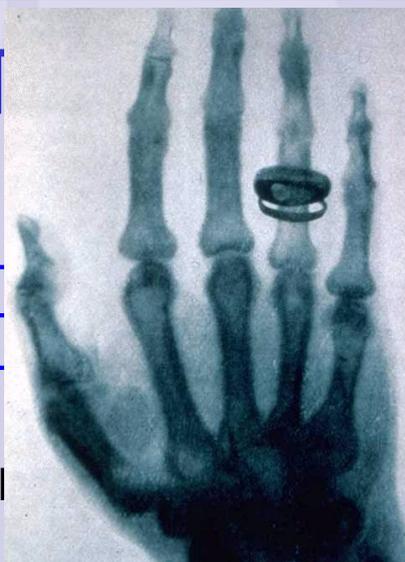
H.C. Kang, J. Maser, G.B. Stephenson, C. Liu, R. Conley, A.T. Macrander, S. Vogt *Phys. Rev. Lett.* **96**, 127401 (2006)



Menu of X-ray Microscopies

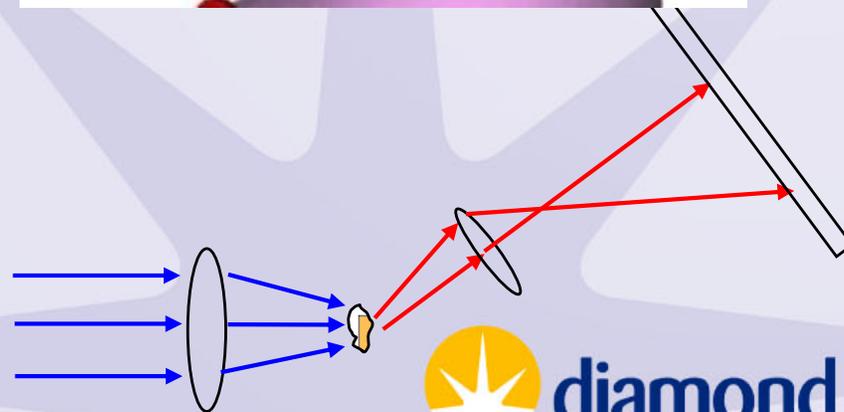
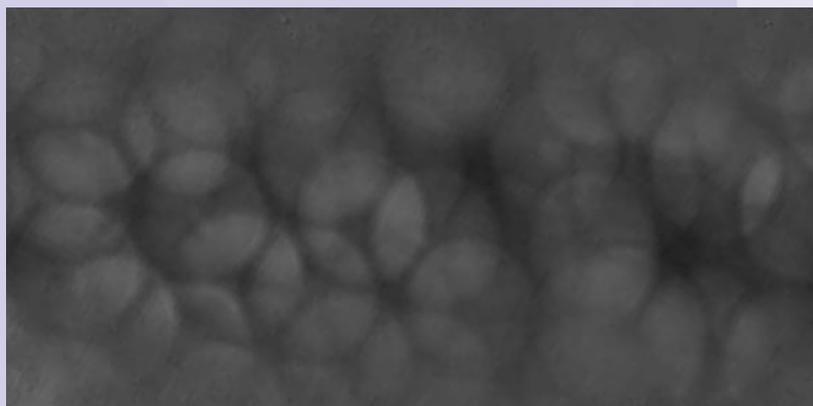
- Hard / ~~Soft~~ X-rays
- ~~Scanning~~ / Full-field
- Phase / Amplitude contrast
- Coherent / Incoherent illumination
- Magnified / Actual size
- Diffraction (dark field) / Transmission

Full-Field Micro



Coherent

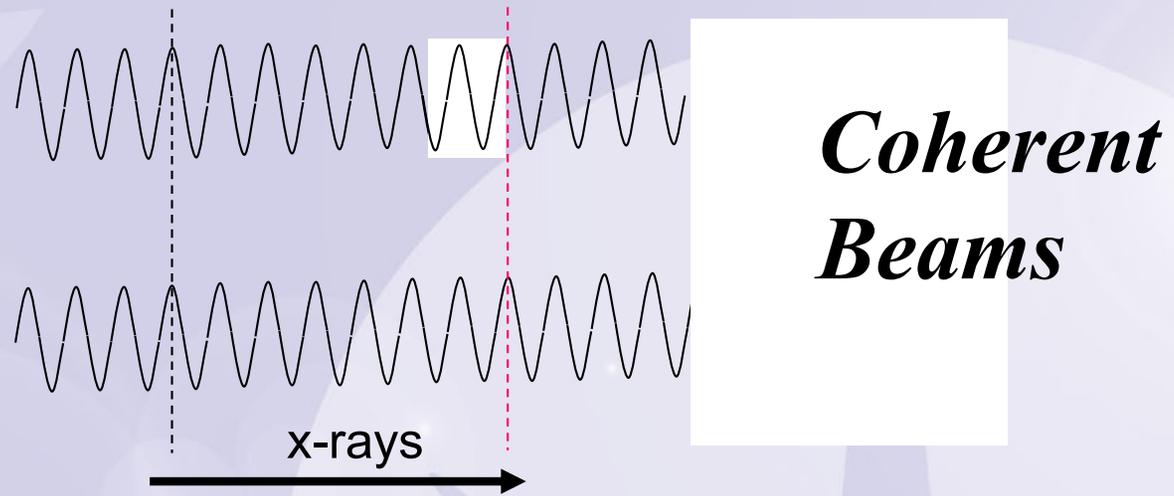
Miao et al (1999)



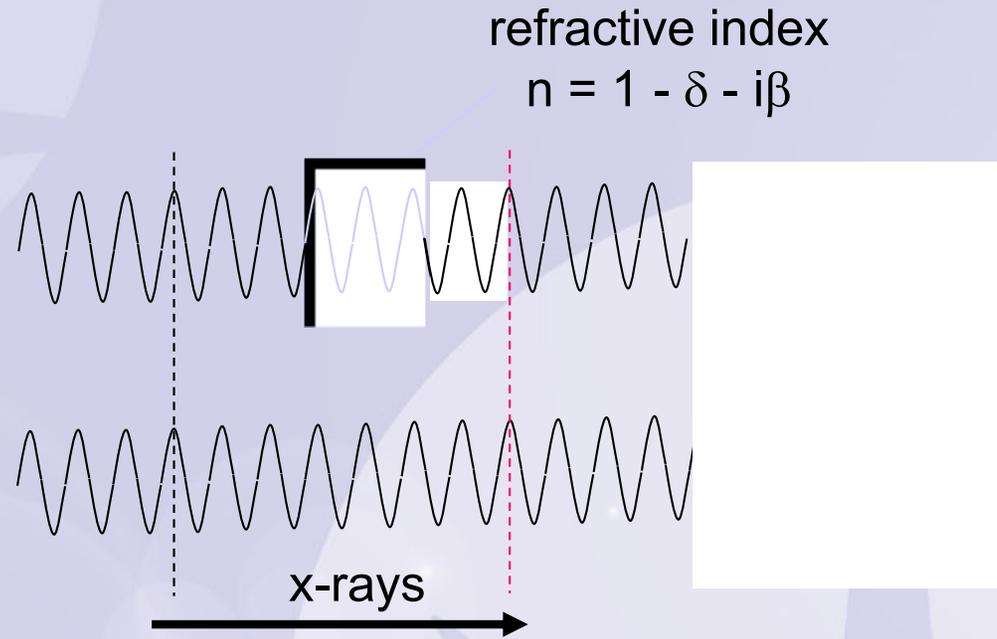
Full-Field Diffraction Microscopy



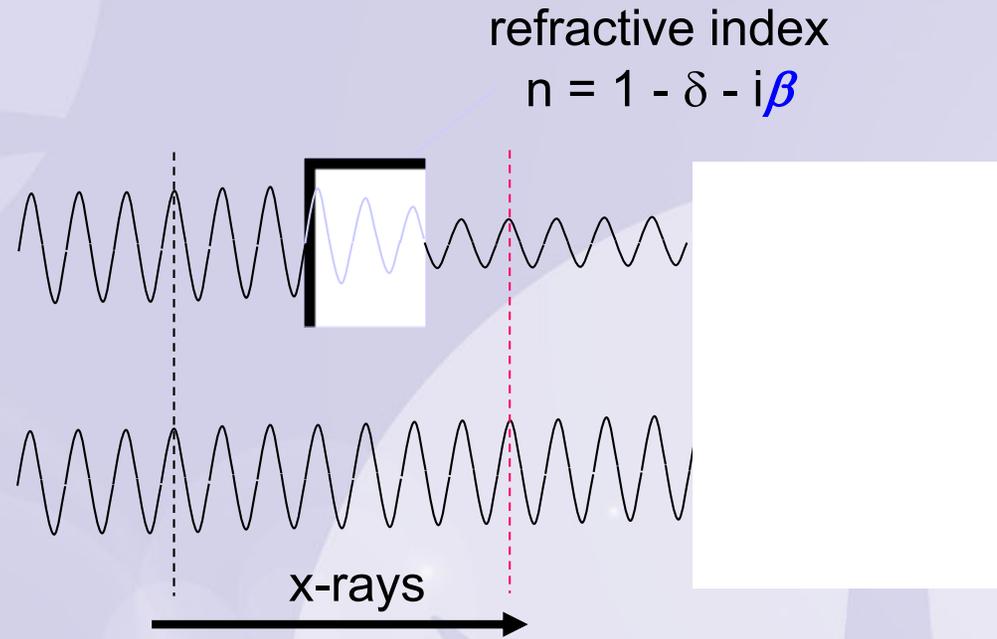
Phase sensitive x-ray imaging



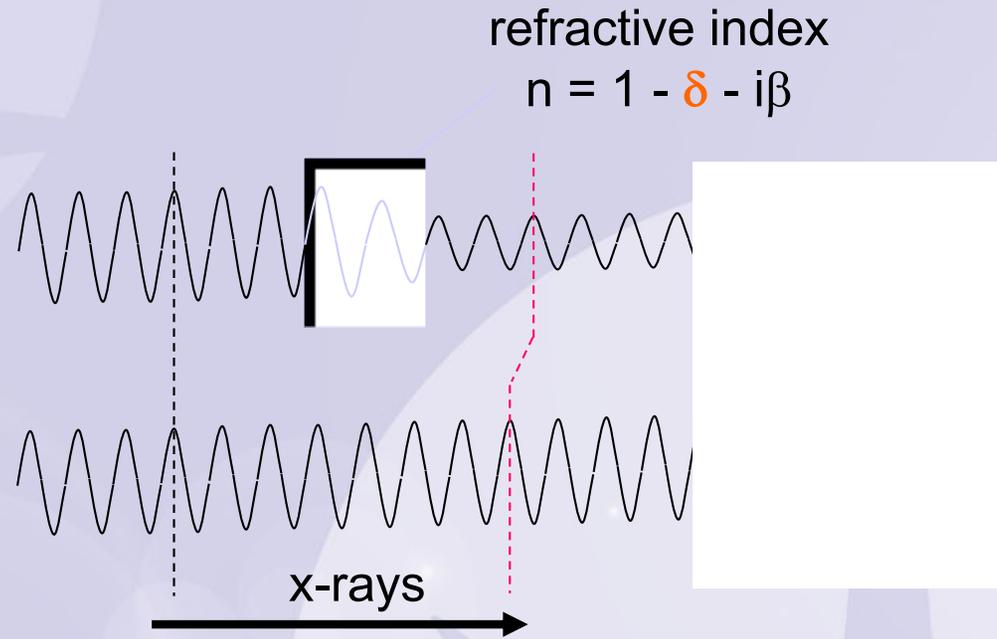
Phase sensitive x-ray imaging



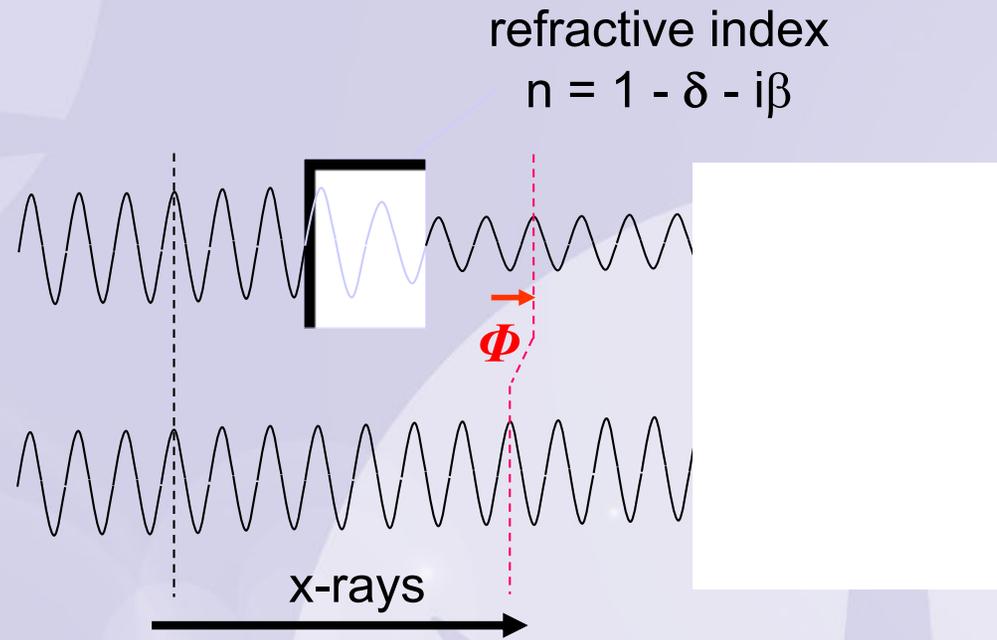
Phase sensitive x-ray imaging



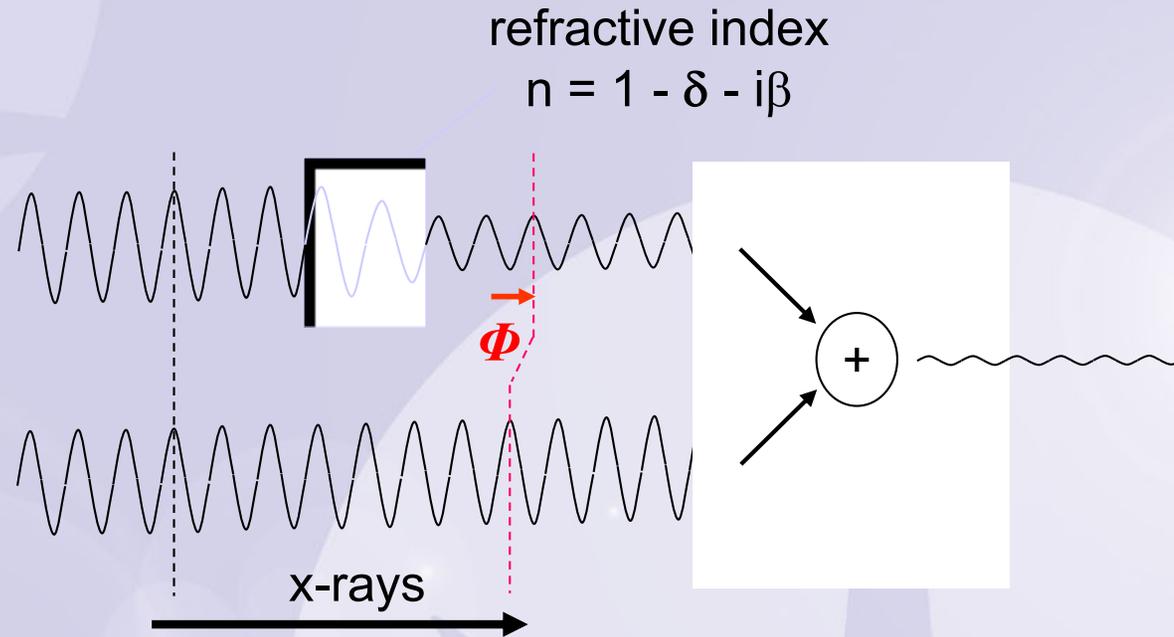
Phase sensitive x-ray imaging



Phase sensitive x-ray imaging



Phase sensitive x-ray imaging

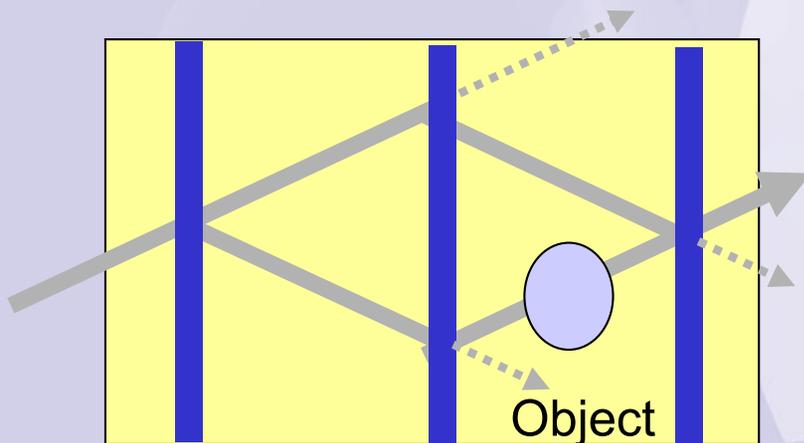
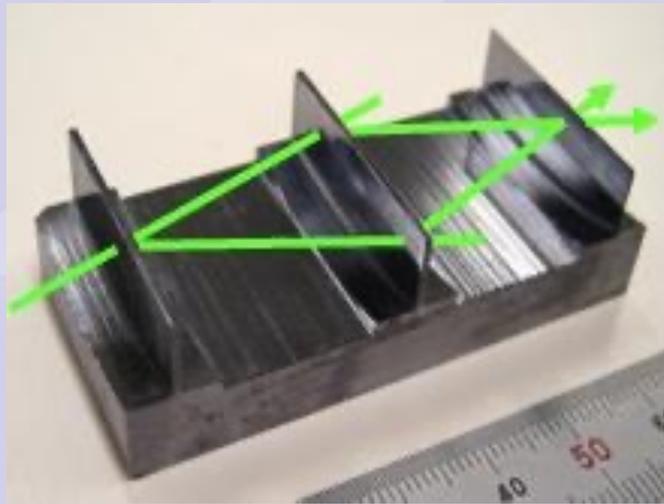


To obtain phase sensitive images, measure:

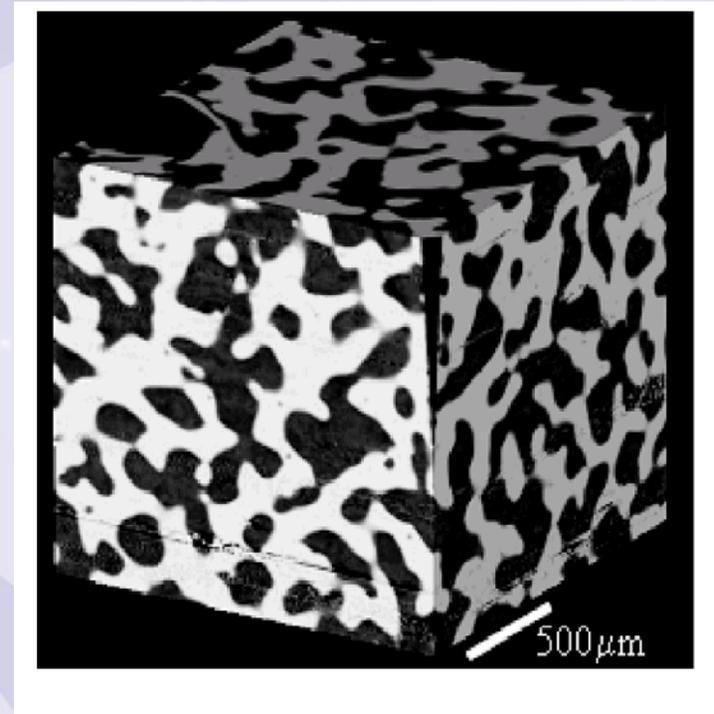
Φ *with a crystal interferometer (Bonse & Hart 1965)*

Crystal Interferometers

Bonse & Hart (1965)

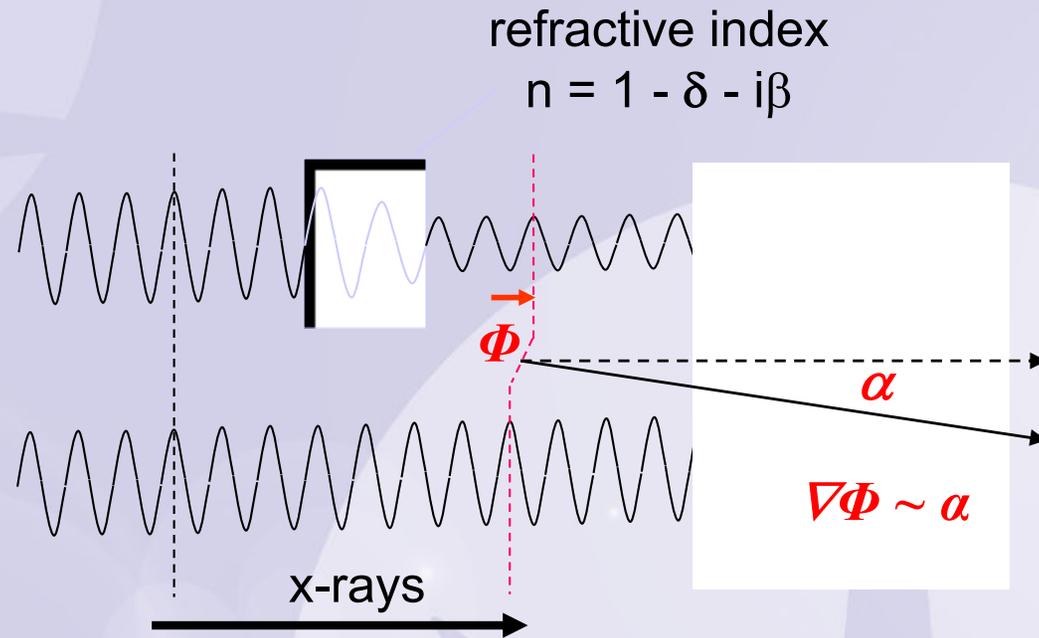


Momose et al. (2005)



PS/PMMA polymer blend
Phase tomography

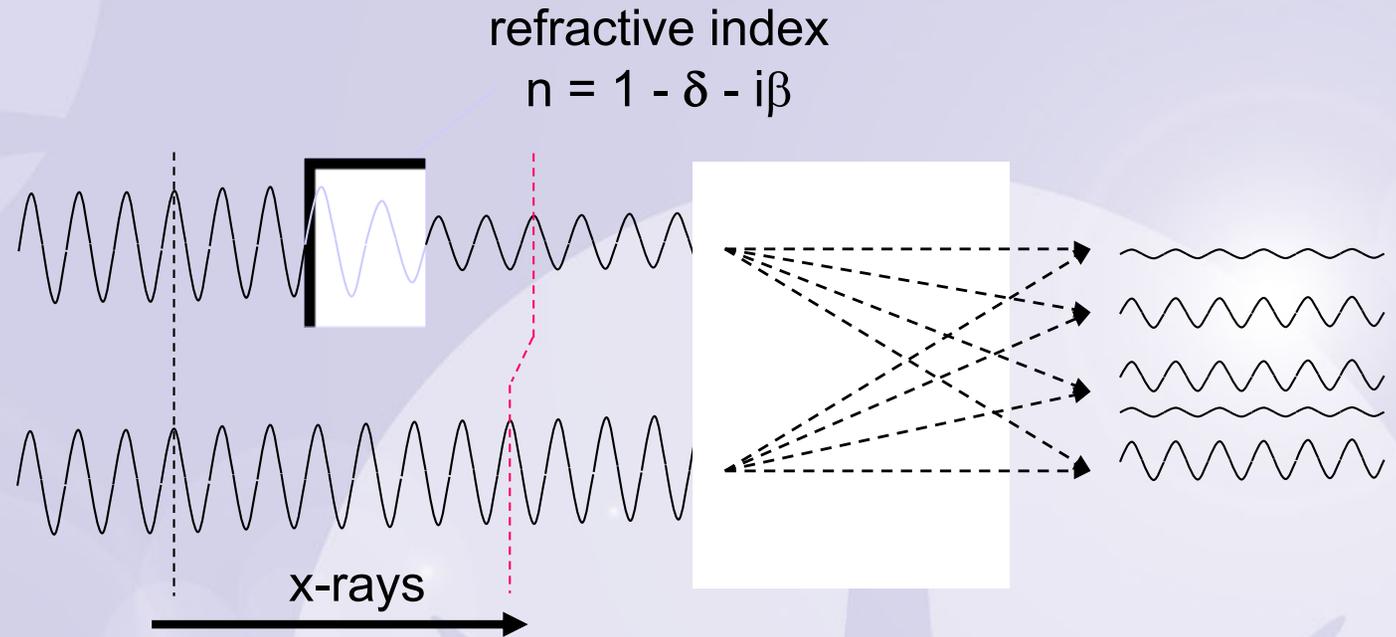
Phase sensitive x-ray imaging



To obtain phase sensitive images, measure:

- Φ with a crystal interferometer (*Bonse & Hart 1965*)
- $\nabla\Phi$ with diffraction enhanced imaging (*Chapman 1997*)

Phase sensitive x-ray imaging

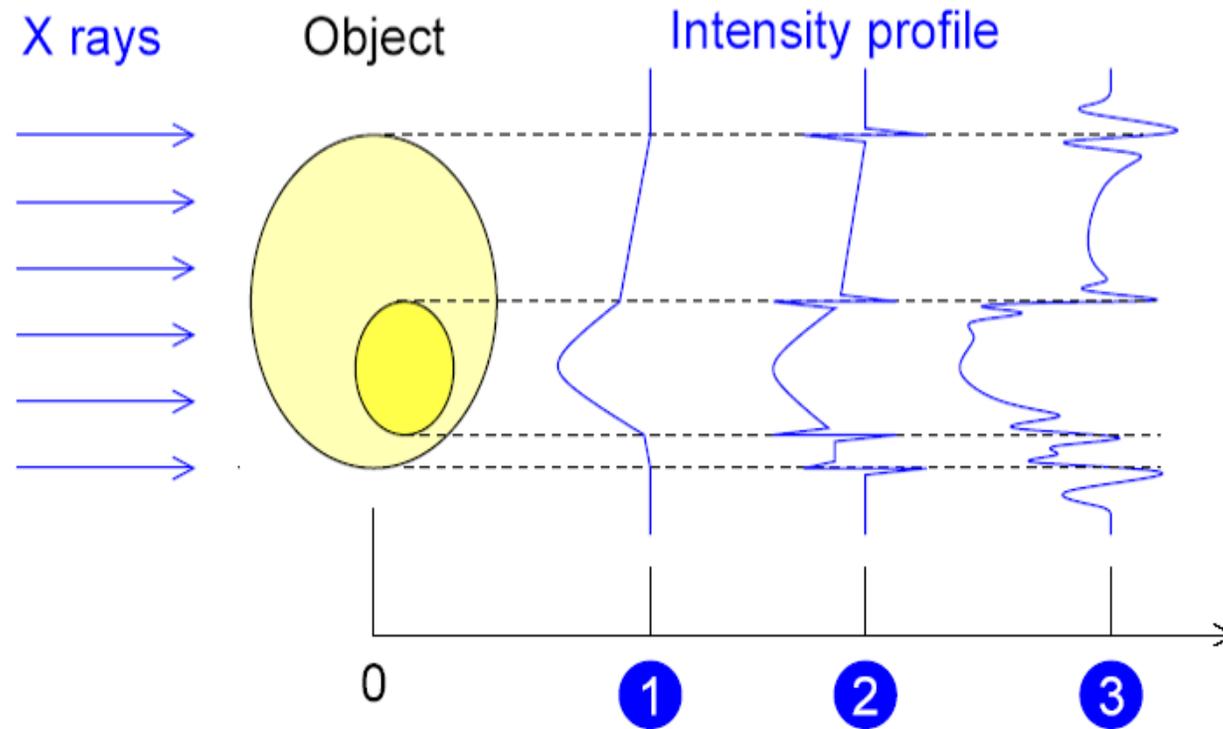


To obtain phase sensitive images, measure:

- Φ with a crystal interferometer (*Bonse & Hart 1965*)
- $\nabla\Phi$ with diffraction enhanced imaging (*Chapman 1997*)
- $\Delta\Phi$ with in-line holography (*Cloetens 1999*)

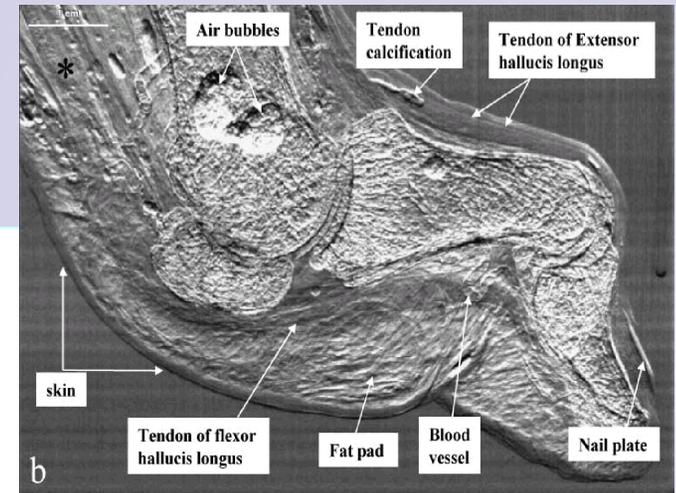
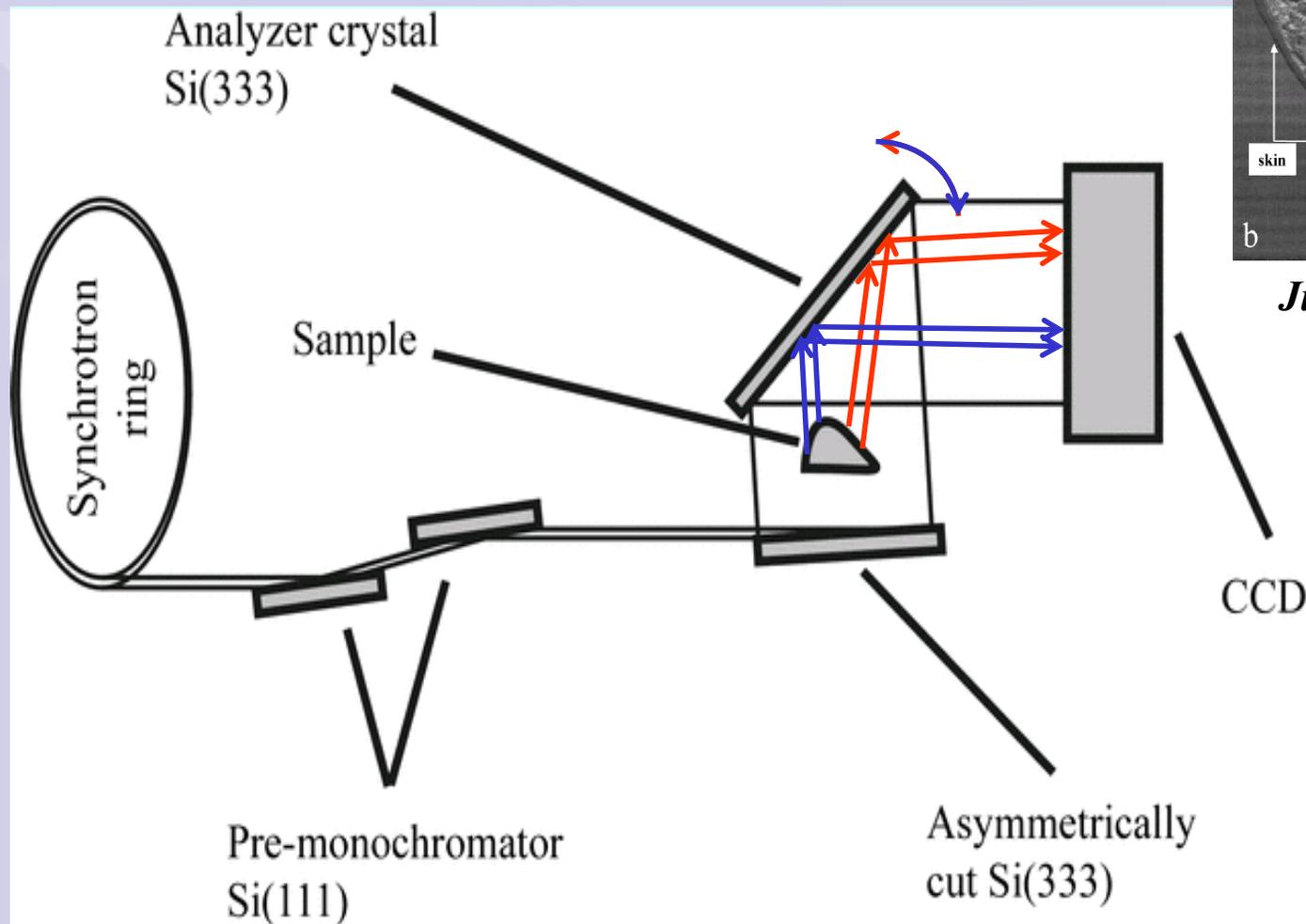
Free Space Propagation

Image formation with coherent illumination:



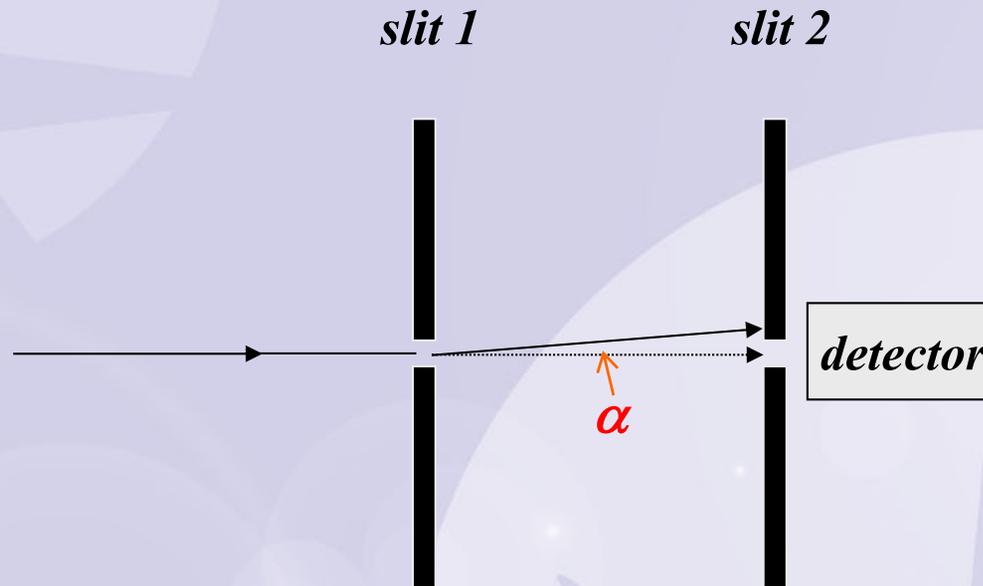
Diffraction Enhanced Imaging (DEI)

Chapman et al. (1997)



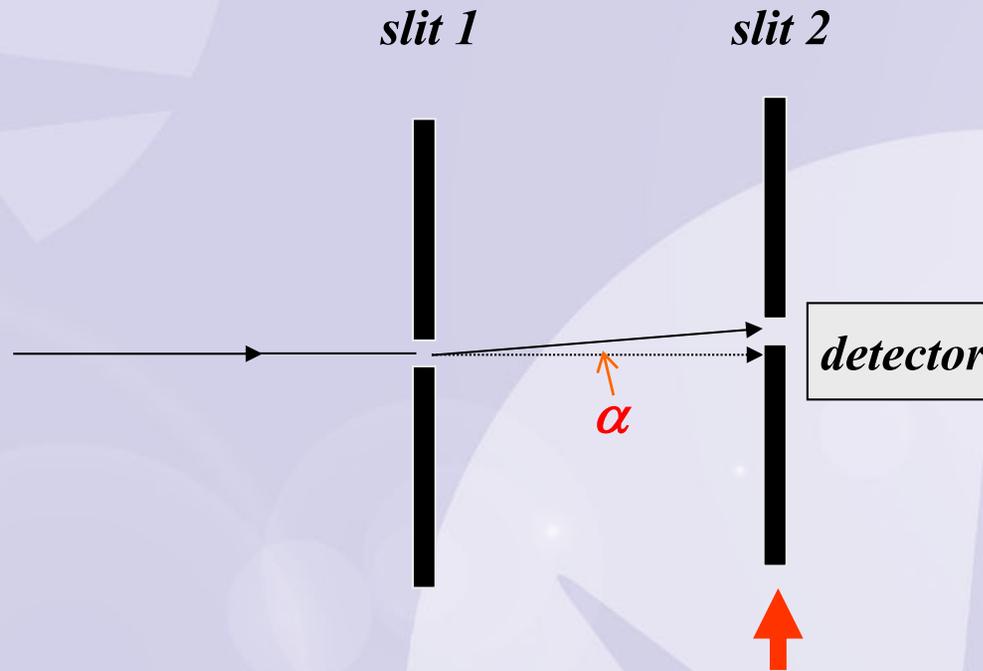
*Jun Li et al., J. Anat 202, 463
(2003)*

Grating Interferometer



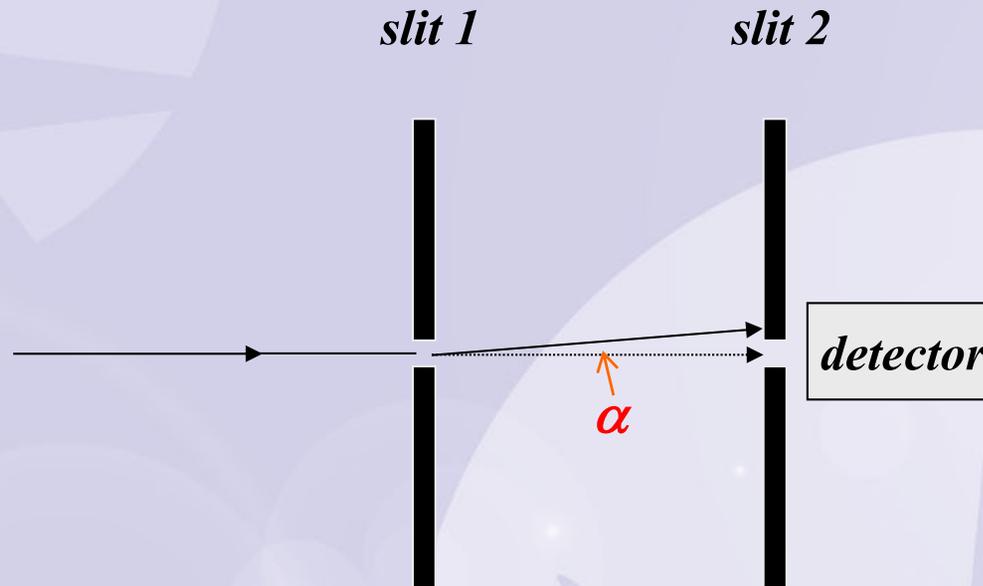
Idea: polychromatic detection of angles

Grating Interferometer



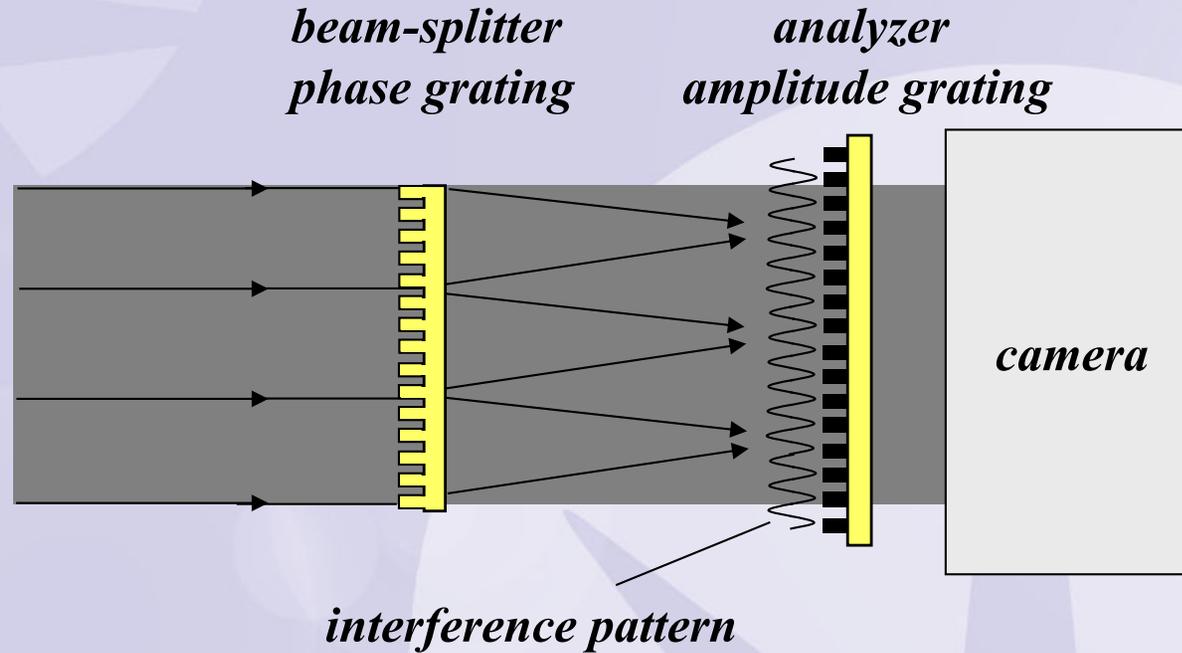
Idea: polychromatic detection of angles

Grating Interferometer



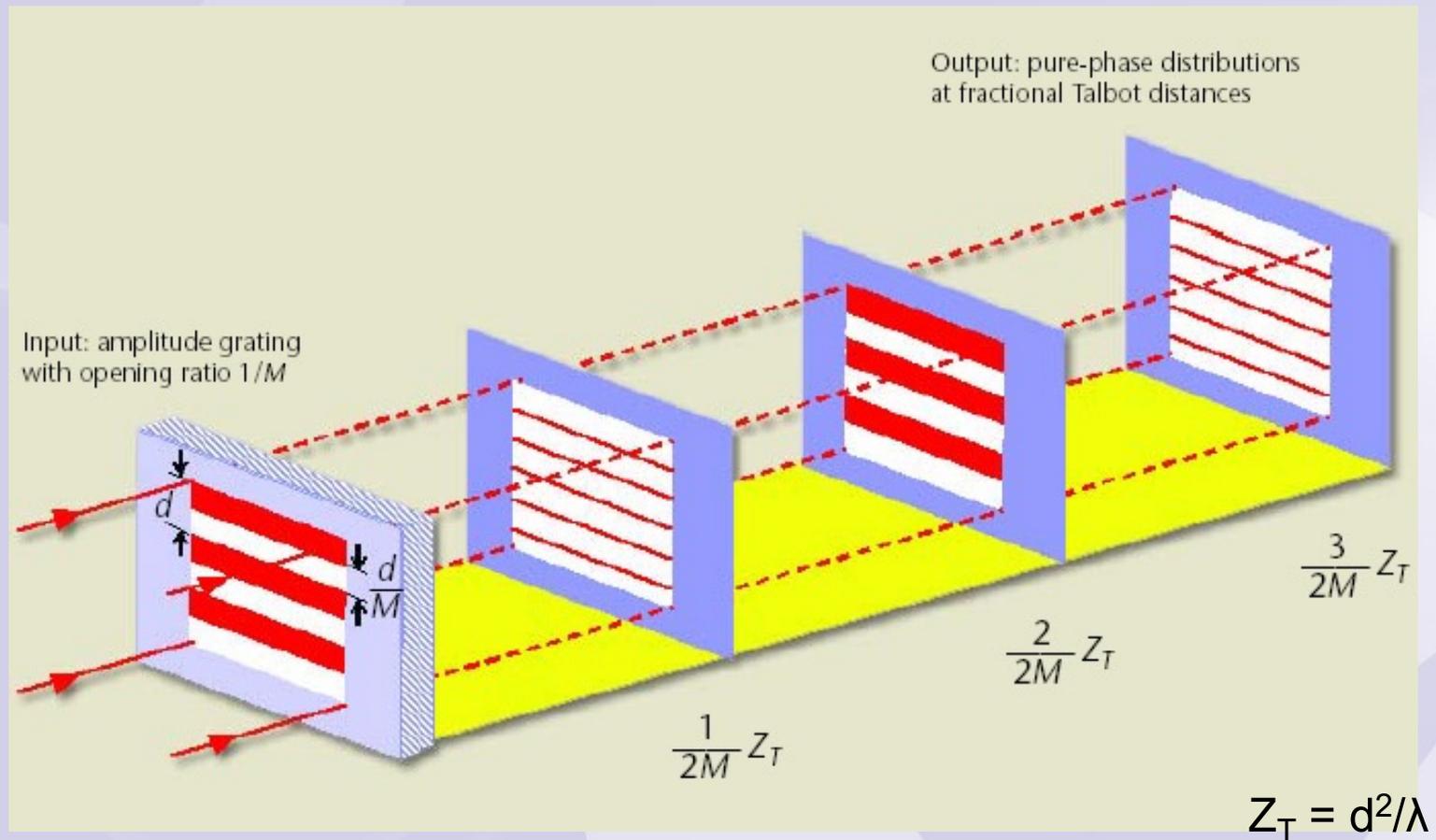
Idea: polychromatic detection of angles

Grating Interferometer



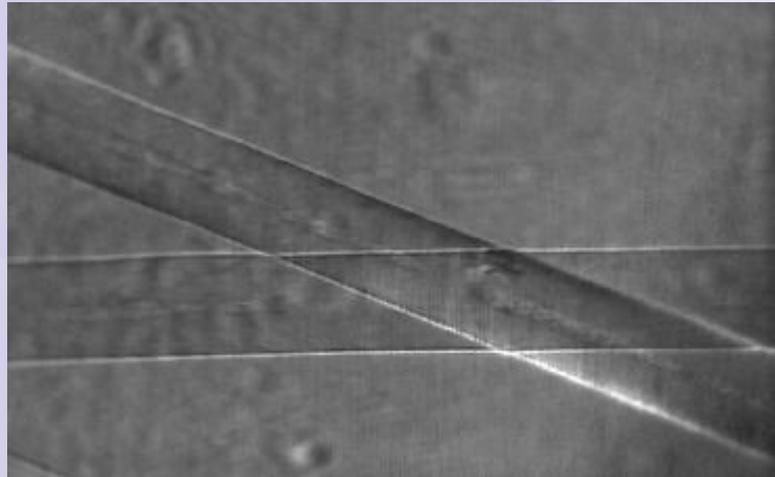
- *phase grating as beam splitter*
- *absorption grating as transmission mask*
- *x-ray wavelength $\lambda \sim 0.1 \text{ nm}$, grating periods $\sim 2\text{-}4 \mu\text{m}$*

Talbot Self-Imaging Effect



C. Zhou et al, Optics and Photonics News, Nov 2004

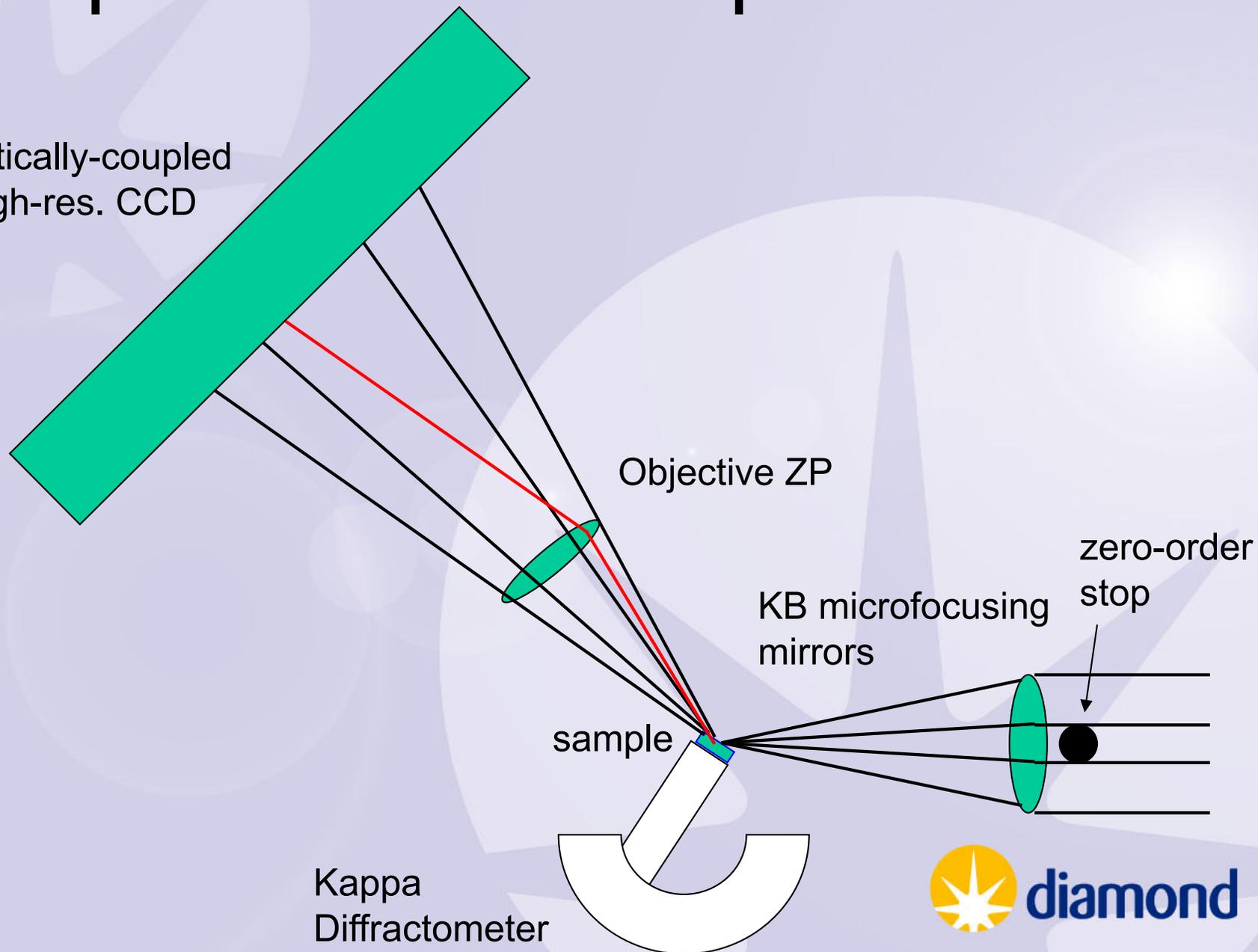
Scan of grating position



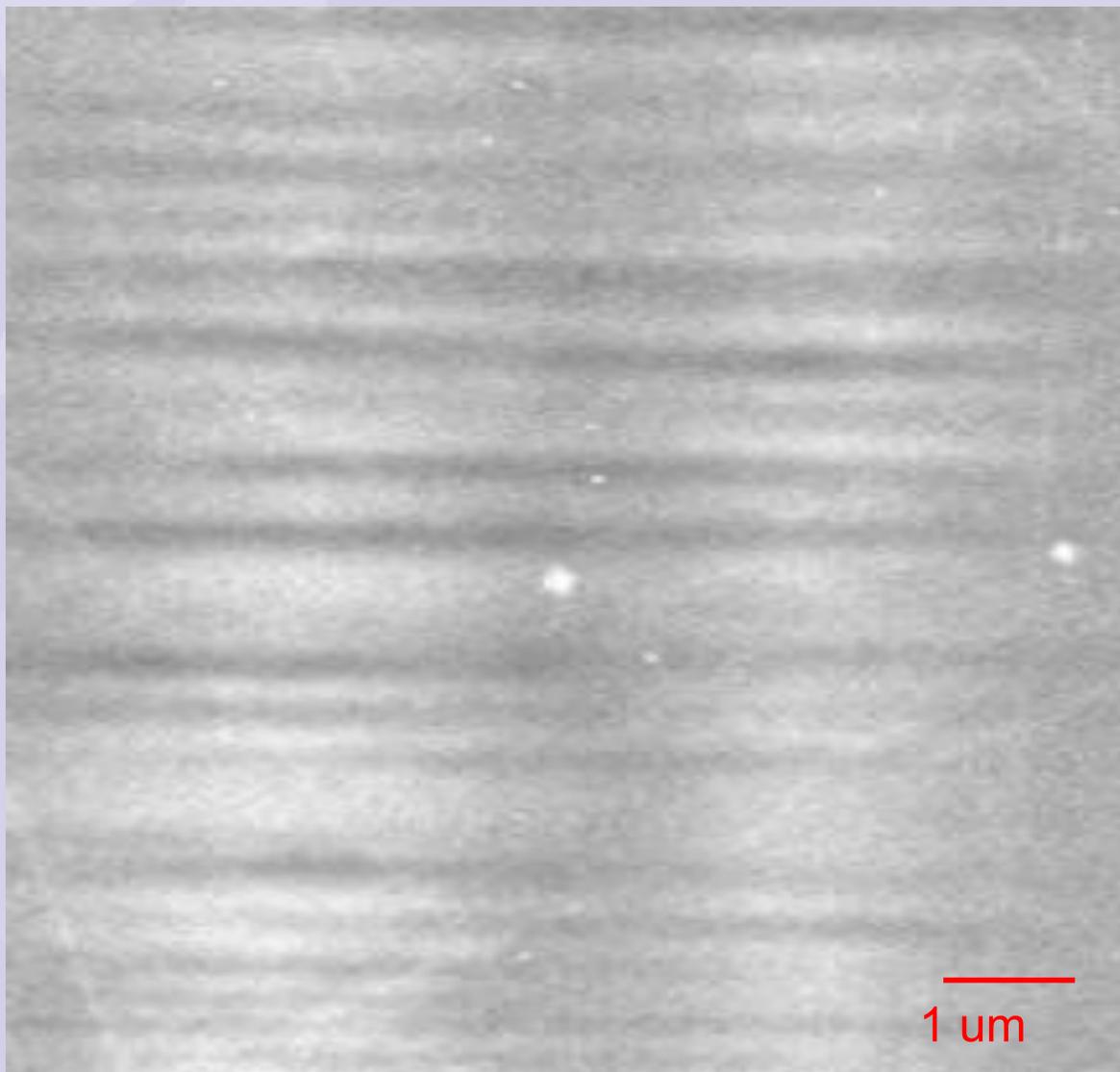
- Energy = 10.05keV FOV 670x410 μm^2 Exposure 500ms
- Camera Kodak Apogee KX2e , 14bit, 9 μm pixel 20X Objective lens,
- YAG scintillation screen with 6 μm thick Eu-doped active layer
- Images 4x4 binned , effective pixel size 1.8 μm , resolution >4 μm

Experimental Setup at 32-ID

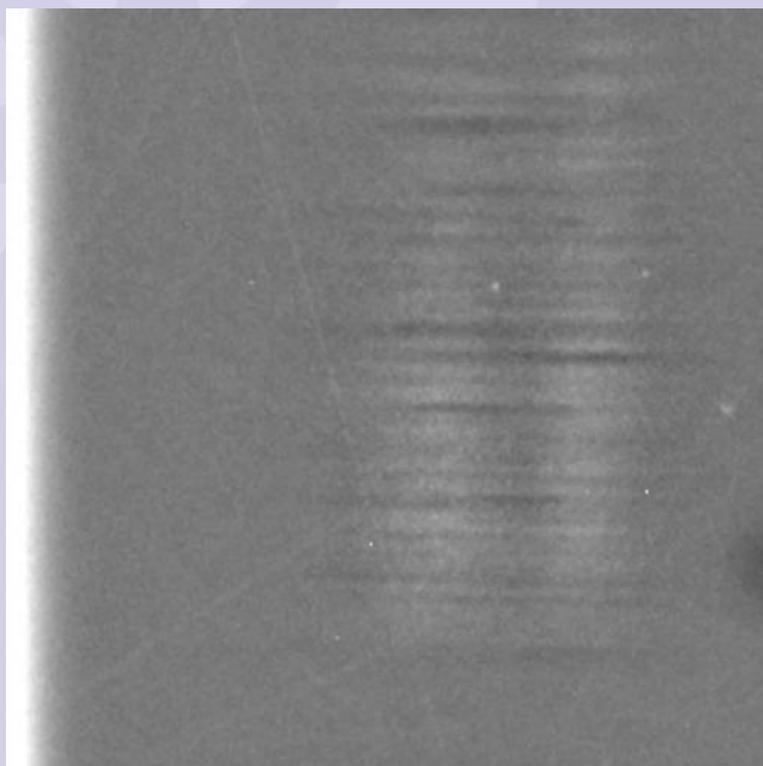
optically-coupled
High-res. CCD



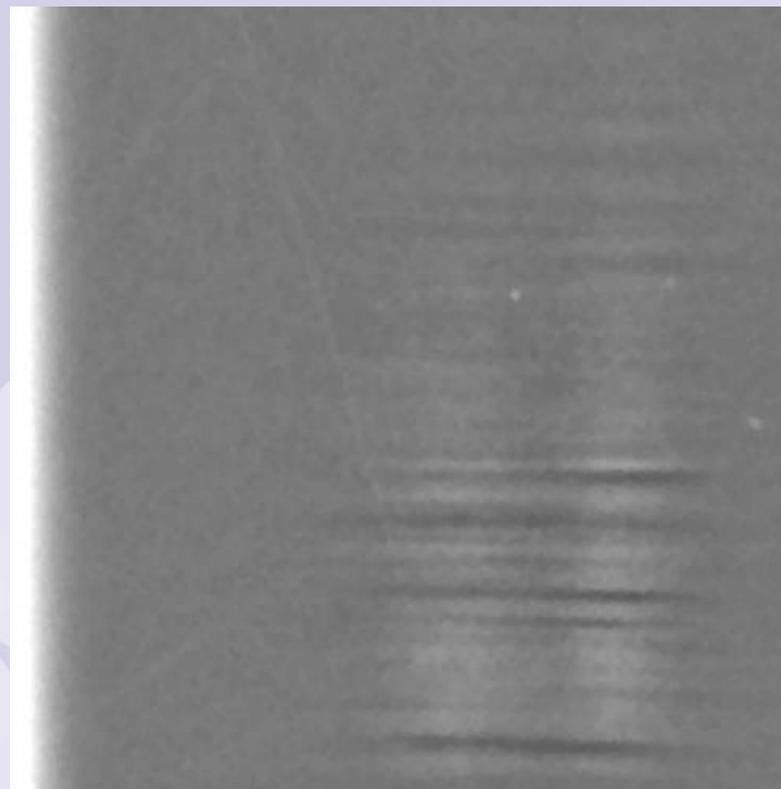
Magnified Real-Space Image of the Surface of RuO₂ (Y. Chu, APS)



Measured at $Q=(0.2, 0.2, 0)$



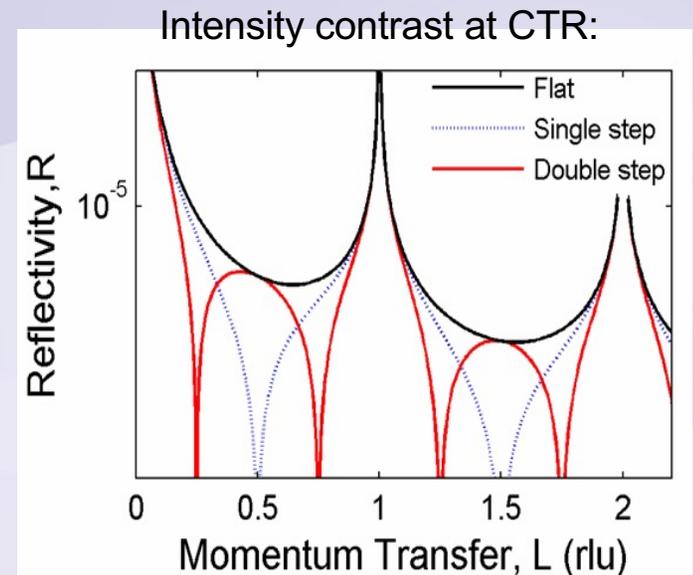
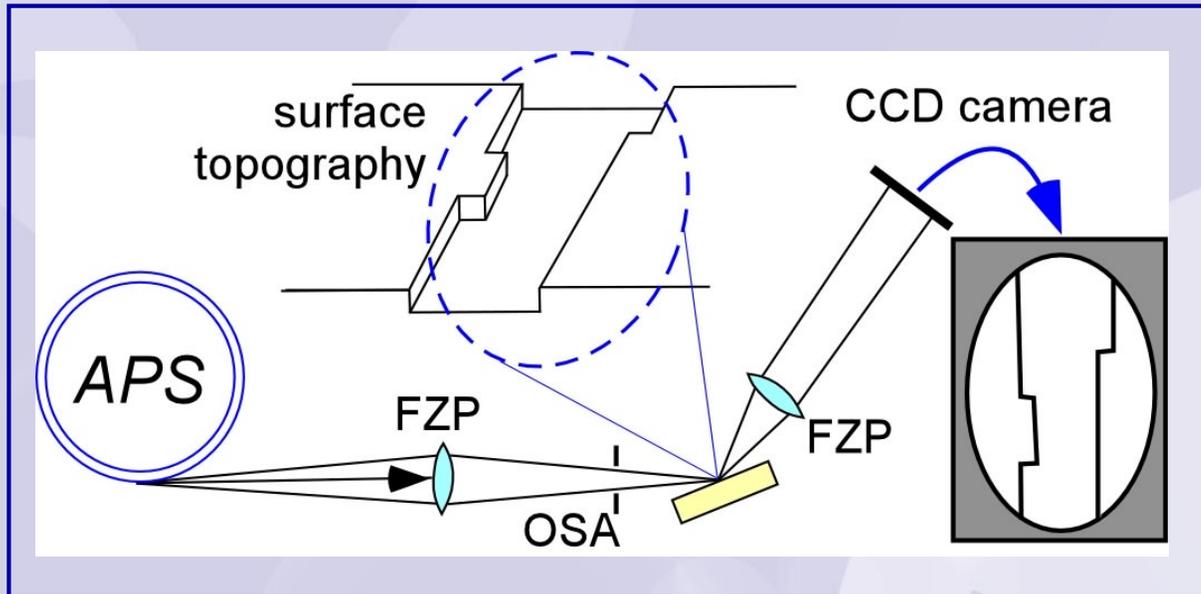
detY=0



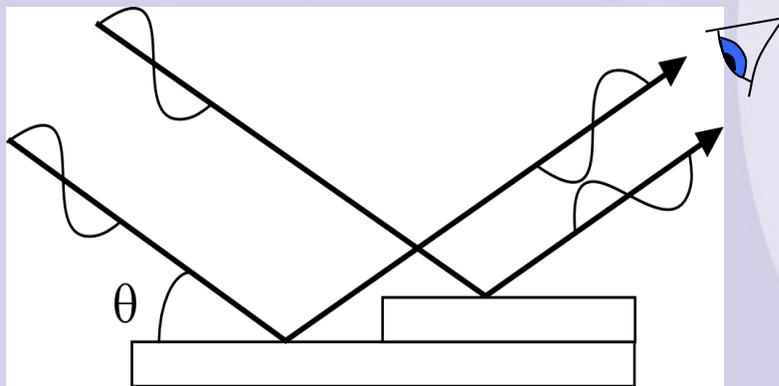
detY=400um

Phase-Contrast X-ray Diffraction Microscopy

*P. Fenter, C. Park, Z. Zhang, and S. Wang, in review (2006)



Phase contrast mechanism:



X-ray Reflection Interface Microscopy

Characteristics:

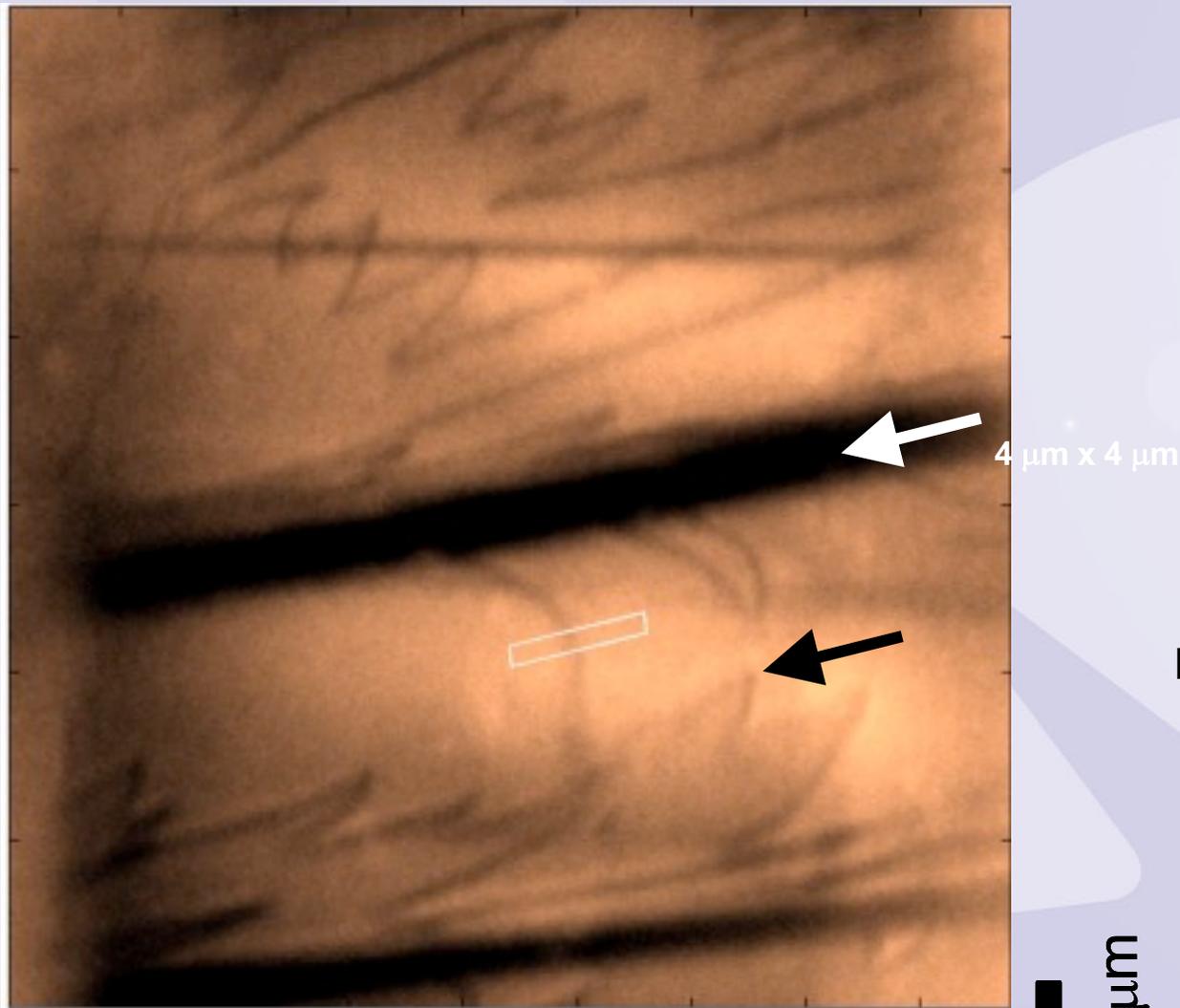
- Strong contrast at defects ($\sim 100\%$), but weak reflected beam intensity ($R < 10^{-5}$)
- Sub-nm vertical sensitivity, but modest lateral resolution (~ 100 nm, set by FZP),

Observation of Surface Step Distributions

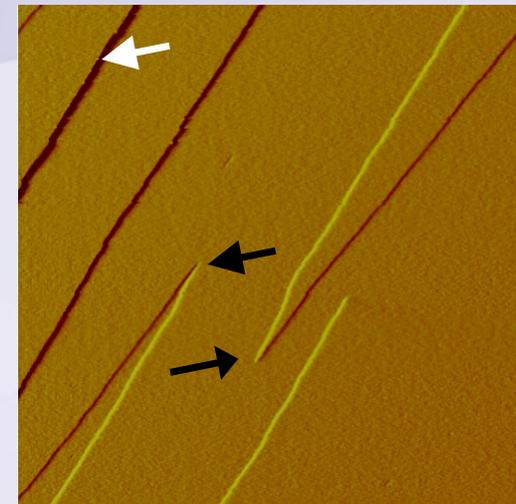
P. Fenter, C. Park, Z. Zhang, and S. Wang, in review (2006)

APS 12-ID-D, December, 2005

Step distributions on Orthoclase, KAlSi_3O_8 (001)



1 μm 40 μm



Teng et al., GCA **65**, 3459 (2001)

Imaging Conditions:

$\theta = 1.4^\circ$

$E = 10 \text{ keV}$

$L = 0.25 \text{ rlu}$ ($Q = 0.24 \text{ \AA}^{-1}$)

Sample held in air



Microscopy at Diamond

- I-18 microfocus, scanning probe
- I-06 PEEM, with side branch
- I-12 JEEP, high energy radiography
- B-22 Infrared Microspectroscopy
- I-13 coherence, CXD

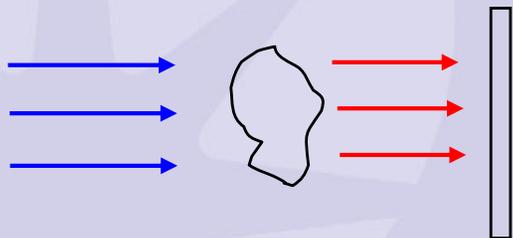
Microscopy at Soleil

- SMIS infrared, 1-10 μ m
- DISCO, 200-900nm, X-PEEM
- LUCIA, 0.8-8keV microfocus
- proposed hard X-ray microprobe
- proposed soft X-ray TXM and STXM

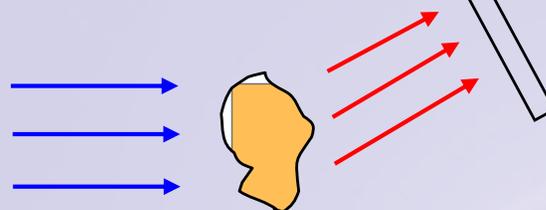
Opportunities for Phase III

- Lens-coupled imaging of diffraction
 - combine with lensless imaging by CXD
- Phase contrast full-field tomography
 - modest coherence requirements
 - magnification by propagation
 - low-beta source (or virtual source)

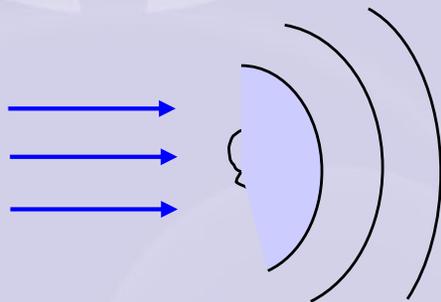
Summary: Hard X-ray Microscopies



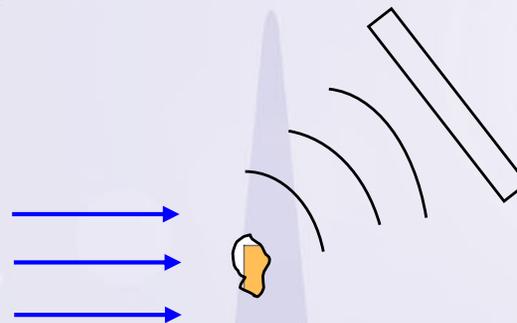
Projection Imaging,
Tomography, PCI



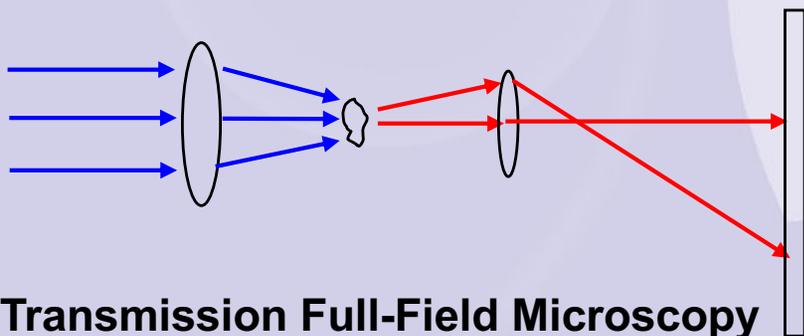
X-ray Topography



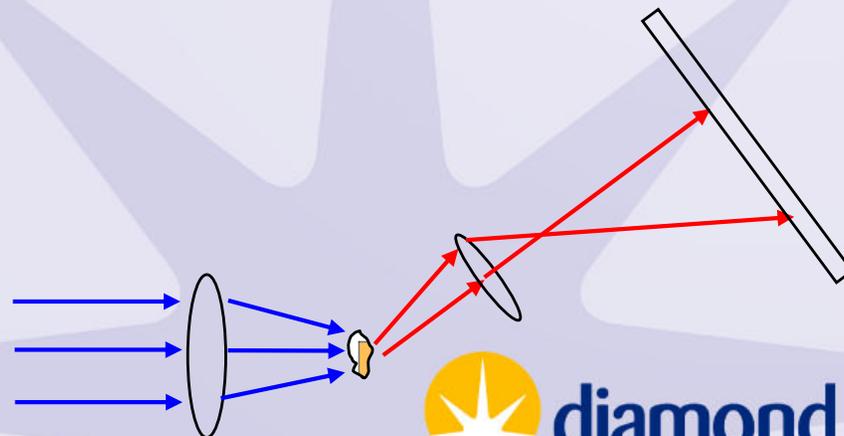
Coherent Diffraction imaging



Coherent X-ray Diffraction



Transmission Full-Field Microscopy



Full-Field Diffraction Microscopy

